



Panasonic Small Cell Testing For AHPS

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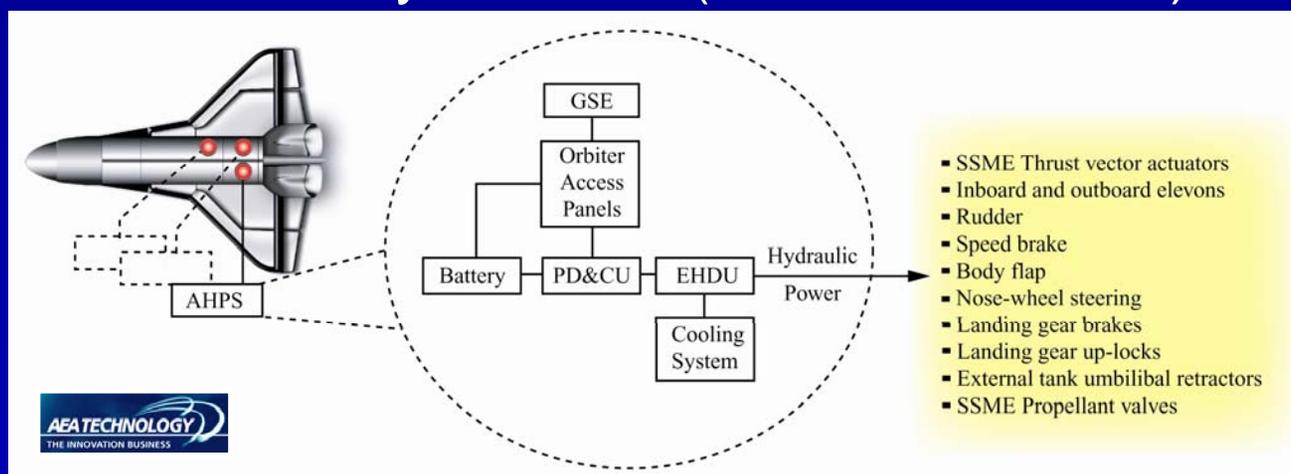
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- Background
 - AHPS Battery
 - Motivation
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AHPS Battery System Overview

- AEA selected in May 2004 to develop the Lithium-ion battery system for the NASA Space Shuttle Advanced Hydraulic Propulsion (System)
- AEA received contract from NASA JSC in Dec 03 to test the Panasonic CGR18650C cell for the AHPS application
- Battery system to provide high voltage electrical power to the Electro-hydraulic Unit (EHDU)
- Battery system: 3 Battery Assemblies
- Battery Assemblies: 2 Battery Modules (series connected)





AHPS Battery Requirements

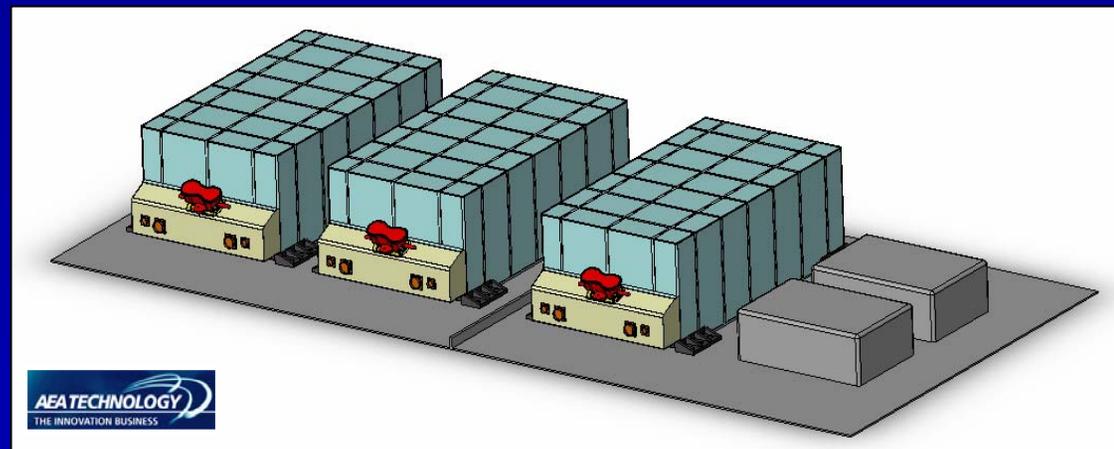
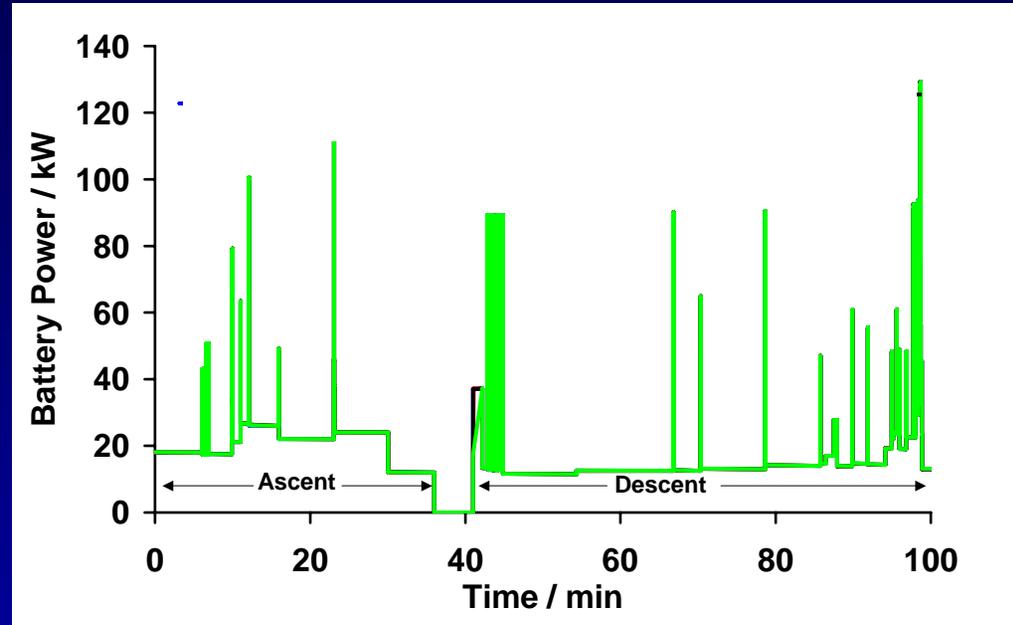
- Output Voltage : 360V – 230V
- Discharge Capacity : 28 kWh
- Maximum Load : 130kW (565A @ min V)
- Low cycle life
- High pulse load

DRIVERS

- Safety and reliability
- Mass
- Cost
- Increase hydraulic flow
- Increase redundancy

MODULE CONFIGURATION

- 43s92p – SONY 18650HC
- Assembly 2s modules





Background: AHPS Battery Challenges

- Large range in battery interface temperature
 - Cold temperature $<10^{\circ}\text{C}$
 - Hot temperature $\sim 60^{\circ}\text{C}$
- Cold temperature
 - Increased internal resistance
 - Low EOD voltage for same load
- Hot temperature
 - Internal protection device (PTC) operates $\sim 70^{\circ}\text{C}$
 - PTC operation dependent in temperature and cell load
 - Upon PTC operation, cell internal resistance rises significantly
- Battery electrical design driven by understanding both cases



Background: Motivation

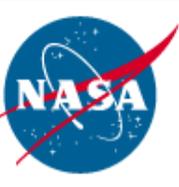
- AEA employs Panasonic cell in terrestrial packs



	Panasonic CGR18650C	SONY 18650 HC
Dimensions	18650	18650
Mass (g)	43	42
Capacity (Ah)	2.15	1.5
Energy (Wh)	7.74	5.2



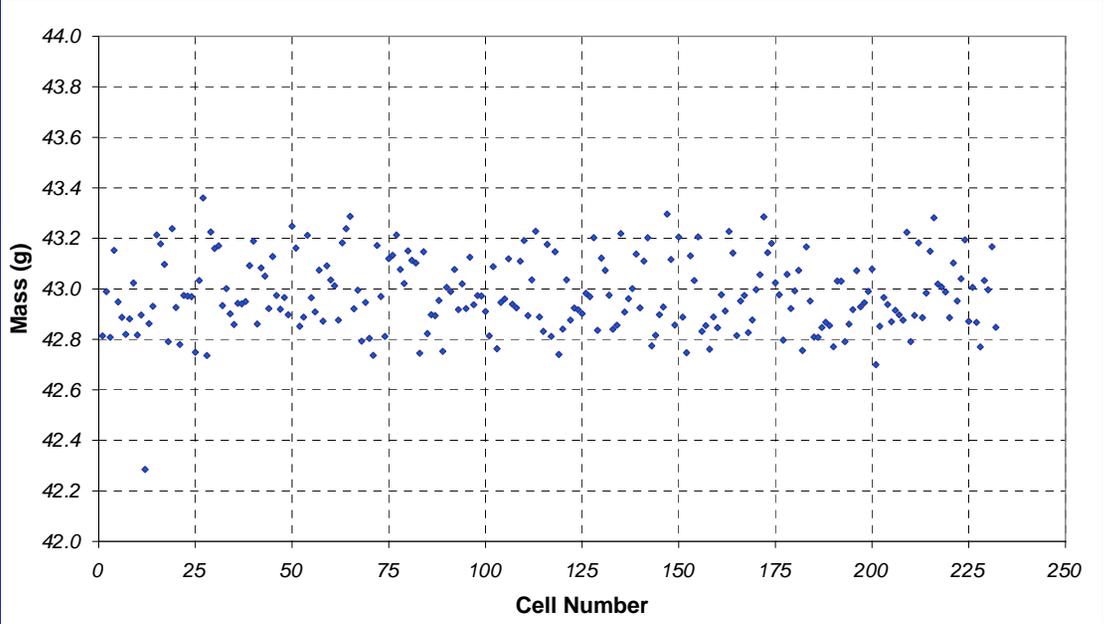
- Test program completed recently
- Test report submitted to NASA
- Main drivers for program
 - Increased performance suggested by capacity
 - Understand Hot case, seen as driving SONY cell battery size



Initial Inspection

Receiving inspection & test (232 cells)

- Mass, volume
- PTC cold resistance
- Stabilisation Cycling



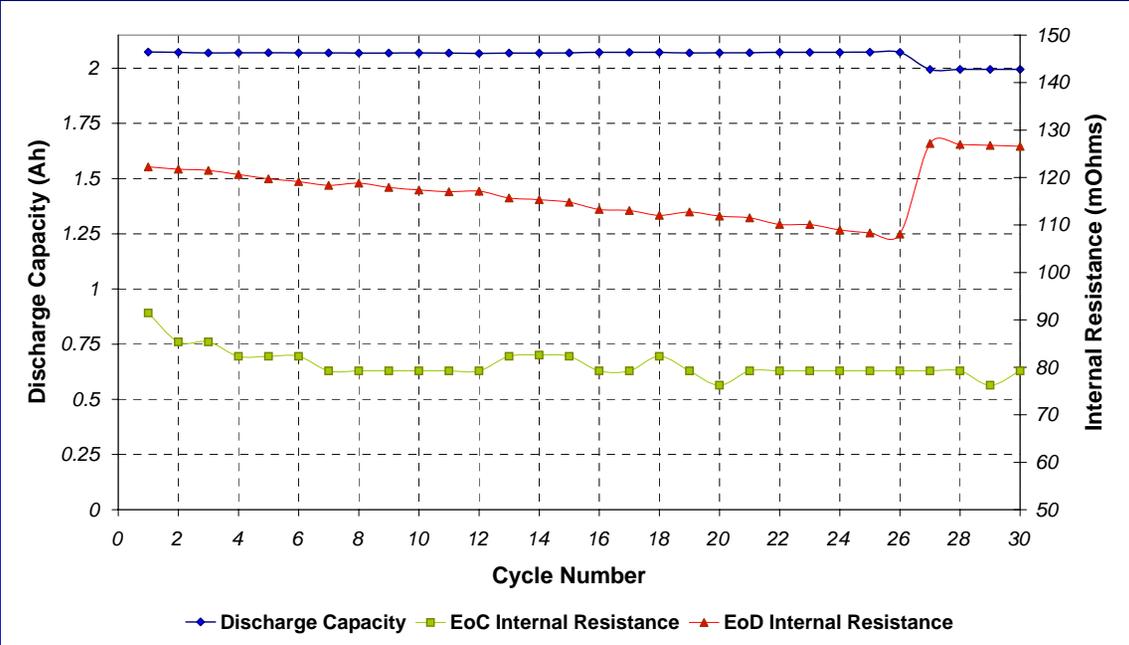
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TEST 14: Cell Destructive Parts Analysis





Capacity under Cycling

- 22°C cycle repeated 30 times
 - 2.59W discharge, 20W pulses (3s/6min)
 - 2.5V voltage limit
 - 1 less pulse cycle 26 onwards

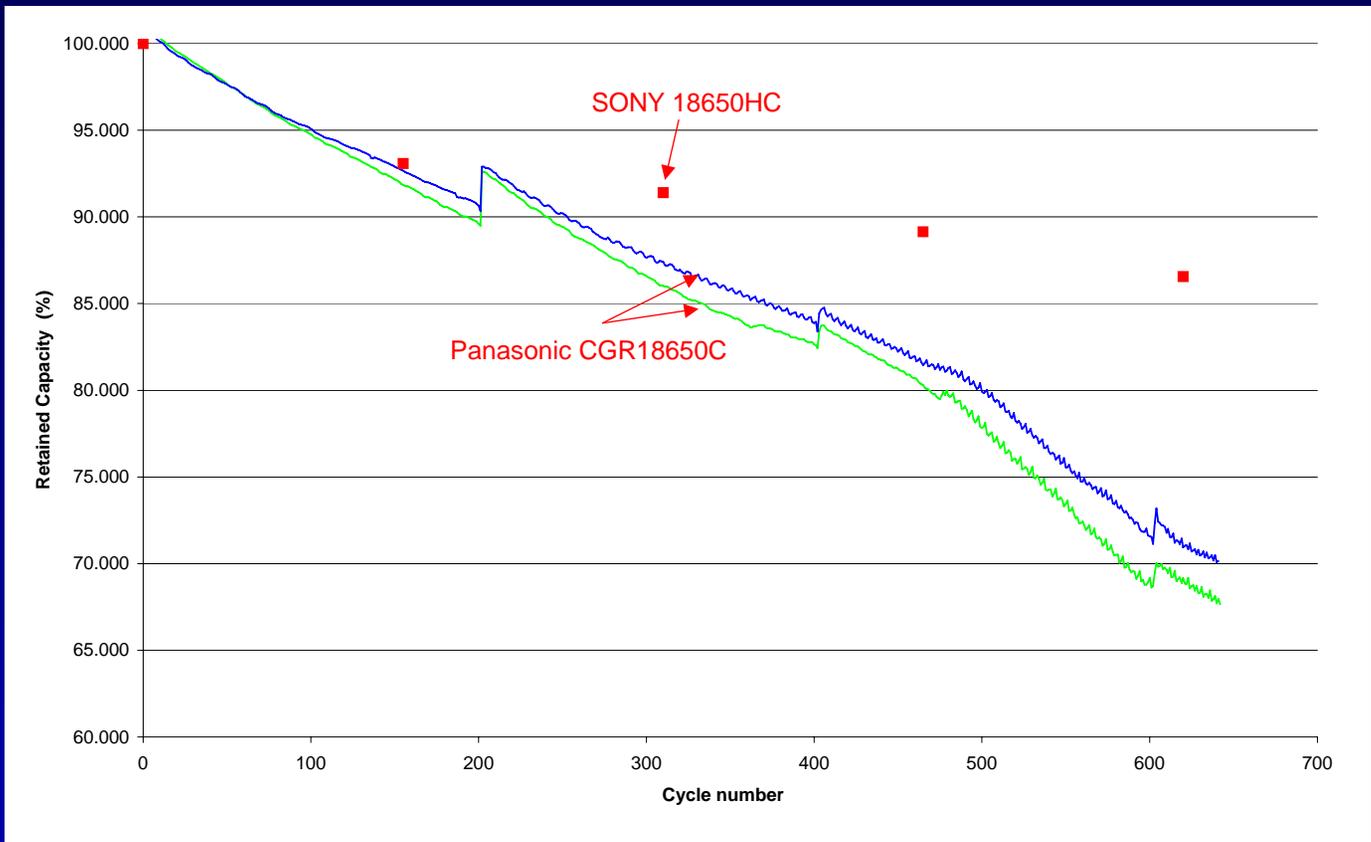


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Cycling Comparison



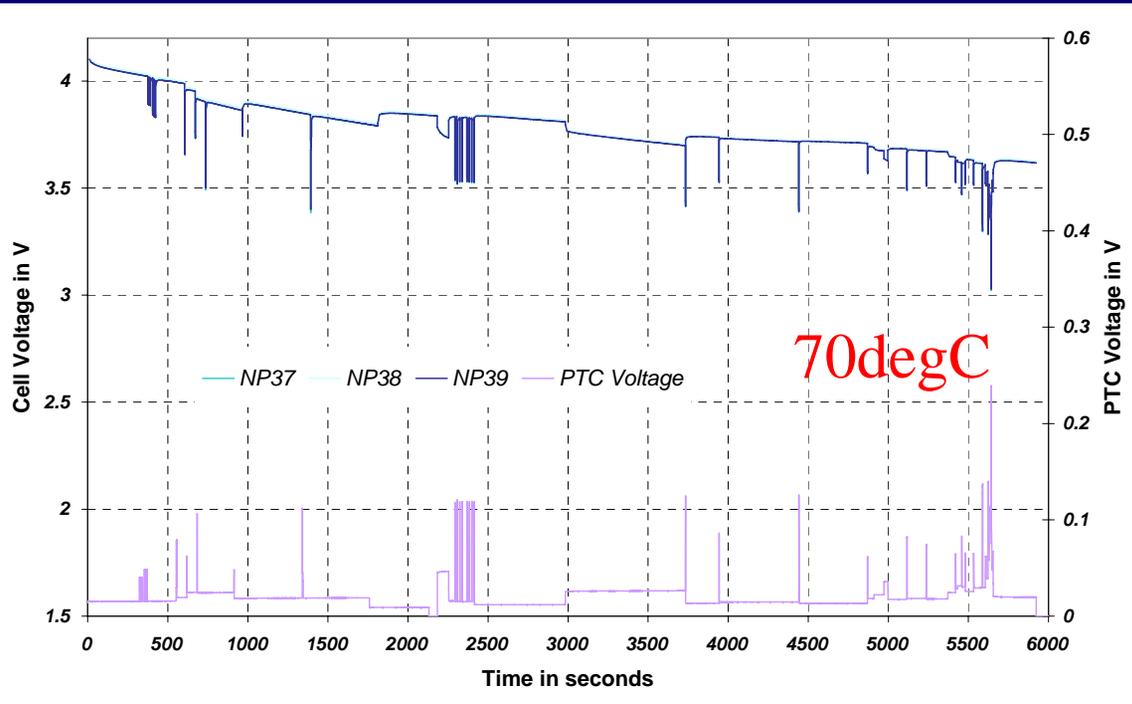
- AEA Internal tests
- 100%DOD
- Ambient temperature





PTC Trip Temperature Evaluation

- Mission profile test – 86s50p
 - 3 cells tested
 - 24°C, 70°C



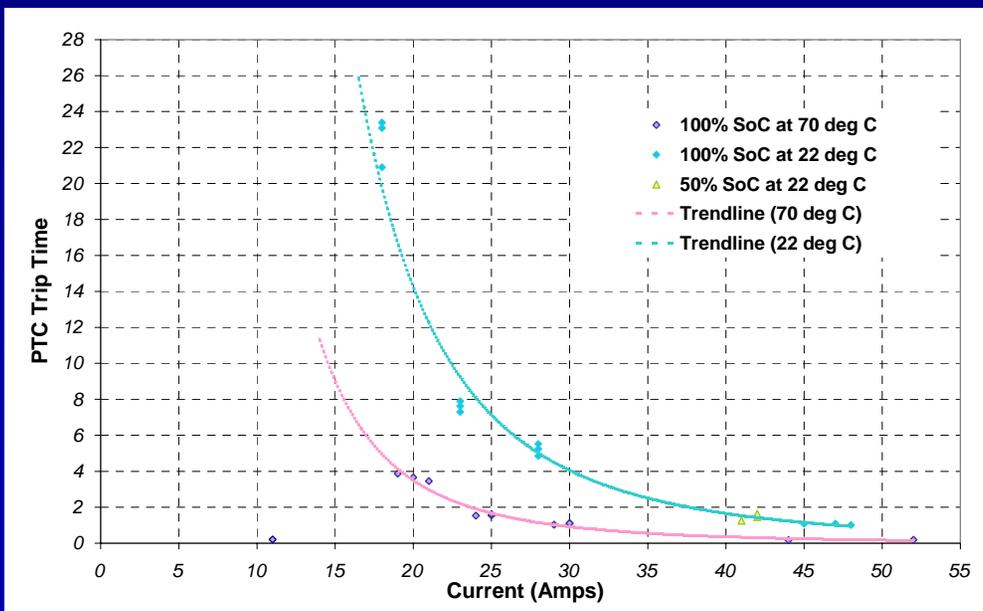
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PTC: Predicting Hot Performance

- PTC characterisation
 - Trip time measured
 - 22 and 70°C
 - PTC trip time is function of current and temperature

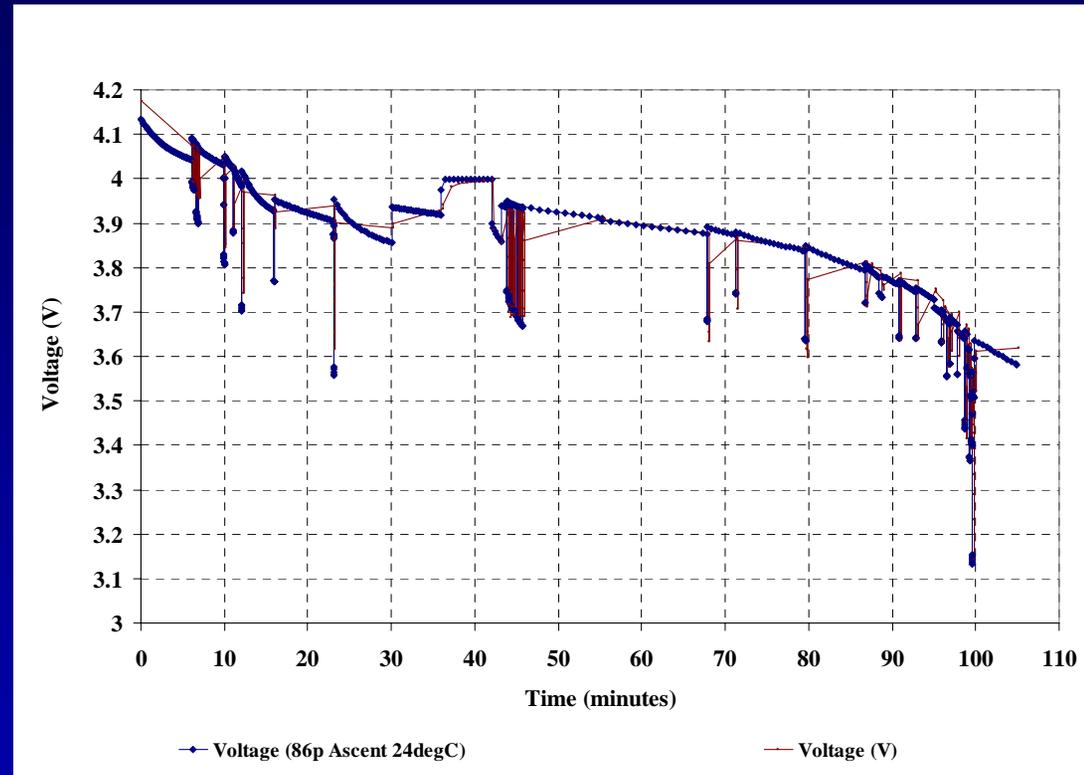


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AHPS Performance Prediction: SONY

- Success modelling SONY 18650HC for AHPS profile
- Key factor for AHPS selection
- Iterative tests to find minimum configuration with Panasonic cell
 - Time consuming tests finding minimum configuration PTC trips
- AEA attempted to modify basic BEAST algorithm for Panasonic cell

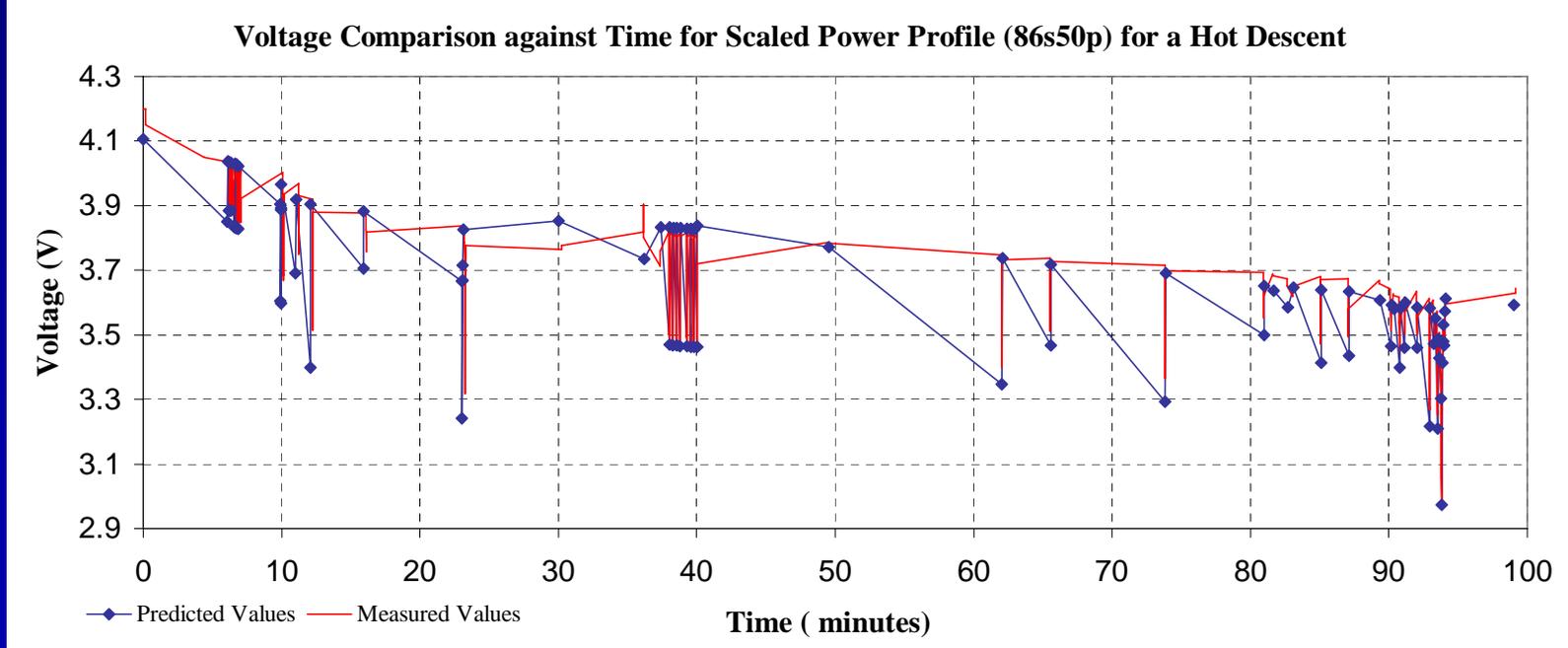




Performance Prediction: Panasonic

- Panasonic measured electrical parameters entered into model
- Performance predictions indicated cold case would drive battery sizing

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Battery Sizing
Voltage
Seal Leakage
ge
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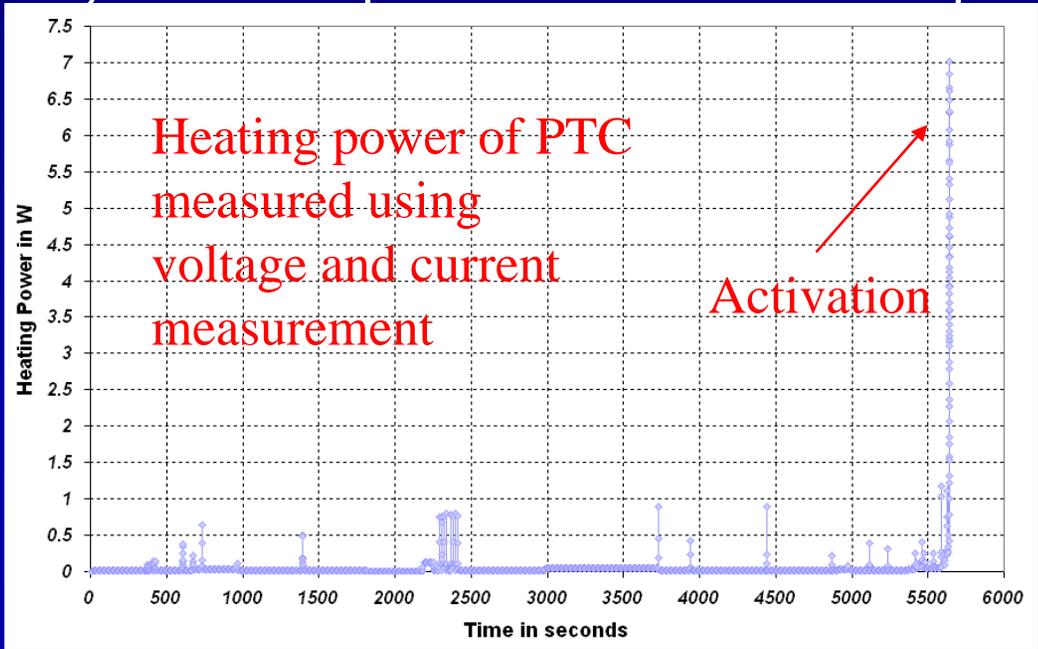
TEST 14: Cell Destructive Parts Analysis





Mission Profile Tests: Hot Case

- Scaled 86s50p mission tests performed:
 - 75°C, 80°C, 85°C, 90°C
- All tests performed on 3 cells
- PTC only begins to activate at 90°C, way above expected AHPS max temp



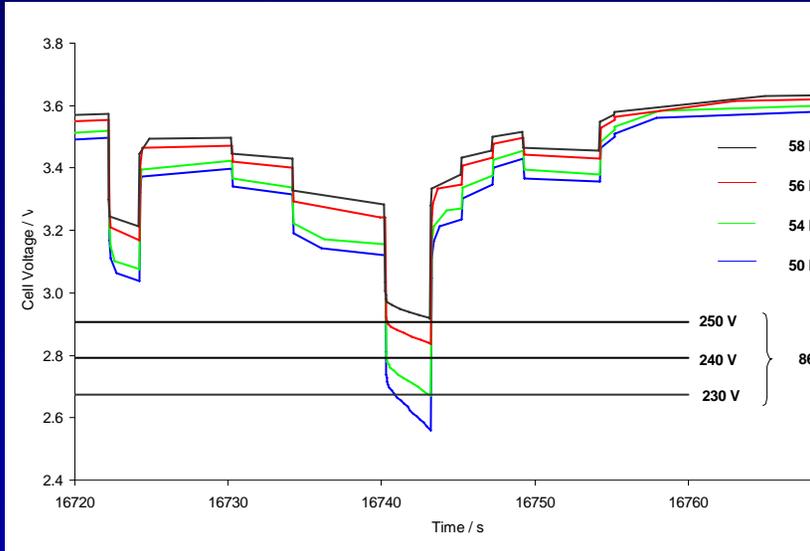
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Mission Profile Tests: Cold Case

- 20degC test
 - 86s: 50p, 54p, 58p, 60p
- Confirmed 54p limit at cold temperature



- HOT CASE: 86s50p, 90degC limit
- COLD CASE: 86s54p, 20degC limit



COLD CASE IS DRIVER

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PTC Withstanding Voltage

- Attempt to measure robustness of PTC to failure under high voltage
- 22degC, placed in series with 15A DC supply
- Results indicated maximum voltage was around 38V – similar to SONY cell
- More representative testing performed at string level on SONY 18650HC
 - Thermal effects from other cells

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Self Discharge and Leakage Test

Temp (°C)	100% SOC	80% SOC	40% SOC	10% SOC
0°C	-	-	-	NP 097, 98, 99
22°C	NP085	NP088	NP089	NP090
40°C	NP086	NP091	NP092	NP093
70°C	NP087	NP094	NP095	NP096

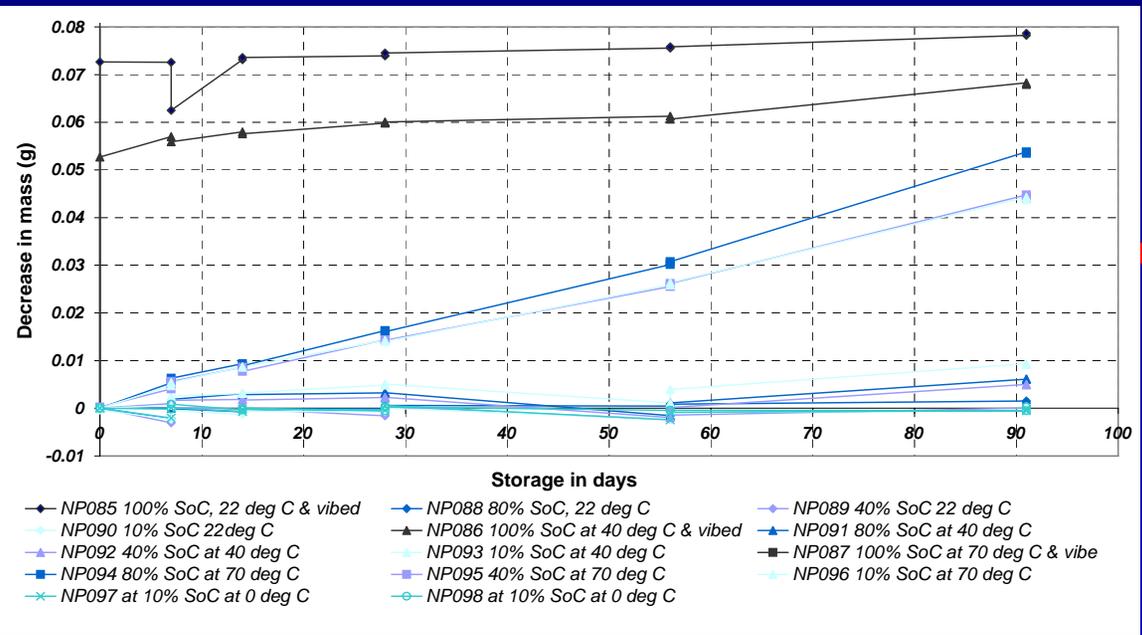
Thermal cycle + Vibration

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Self Discharge and Leakage Test

- Cell NP087 damaged during removal from vibe jig
- Thought leakage in NP085 and 086 could be due to similar problem
- High temp mass loss thought to be due from chemical dissociation and gas release



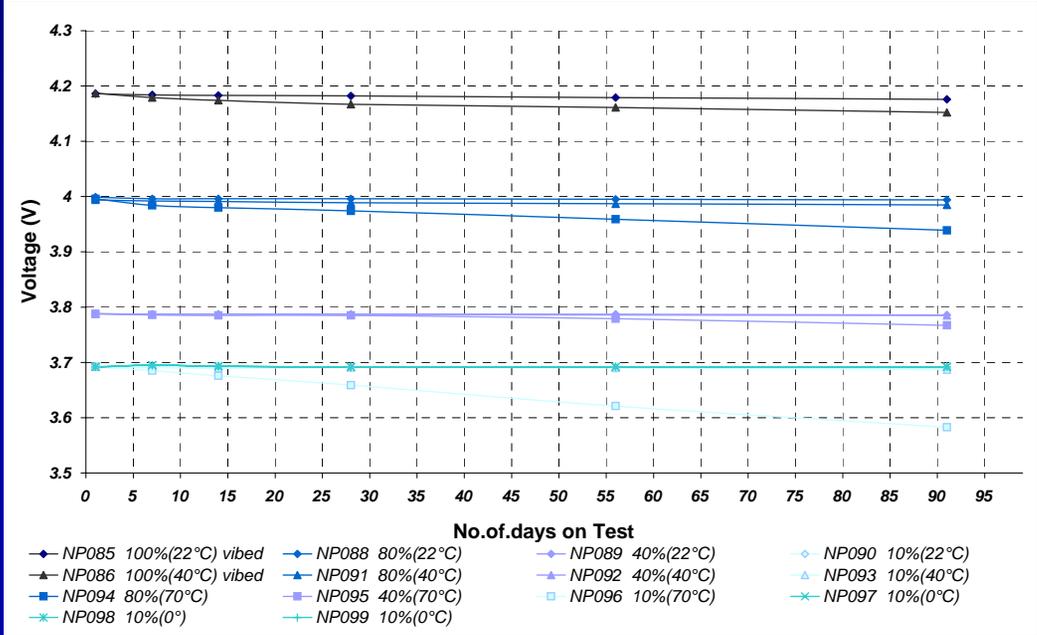
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Self Discharge and Leakage Test

- Low voltage drop due to self-discharge
- Self discharge increase with temperature evident in 10%SOC plot
- Test error meant capacity loss from self-discharge could not be differentiated from irreversible capacity loss



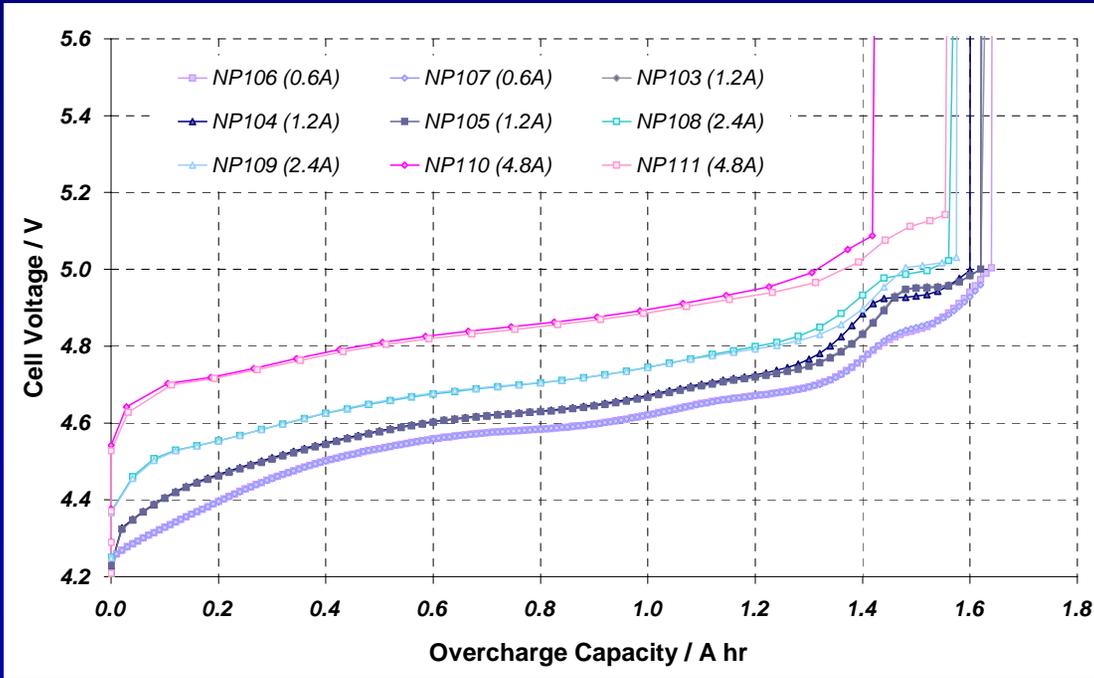
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Cell Overcharge

- Charged to 12V, fixed currents
 - 0.6A, 1.2A, 4.8A
- All 6 cells disconnect close to 5V
- Matched other dedicated testing at 1.2A



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Cell Overdischarge

- Fully charged cells discharged
 - to 2.5V held for 60mins (@XAmps)
 - to 2.0V held for 60mins (@XAmps)
 - to 1.0V held for 60mins (@XAmps)
 - Charged back to 4.2V (@0.43A)
 - Discharged to 2.8V (@0.43A)
 - Discharged to 0V (@XAmps)
 - Discharged at 1.2A to 150% of 1C
- 3 cells each at X=1.2A, 2.4A, 4.8A
- At negative voltages, all cells soft short and act as resistors

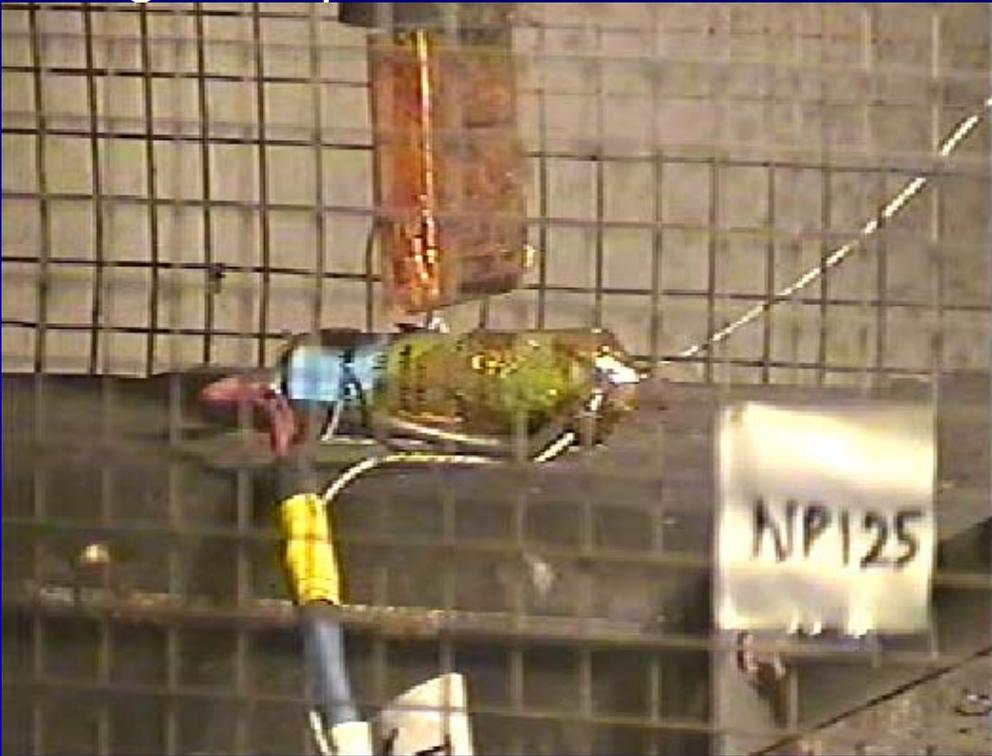
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Cell Internal Short Circuit

- 3 fully charged cells
- 25°C±5°C
- Non-metallic crush rod through cell centre
- Voltage, temperature monitored



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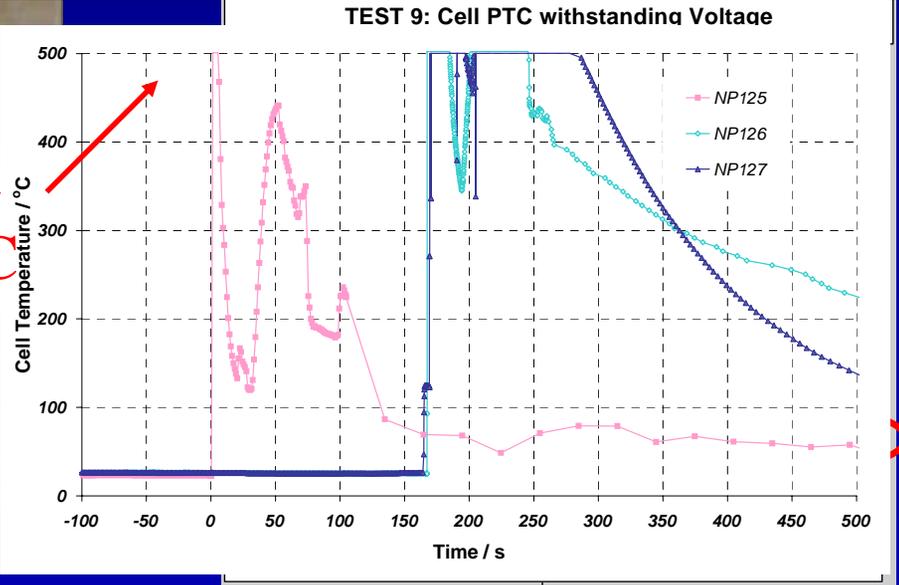
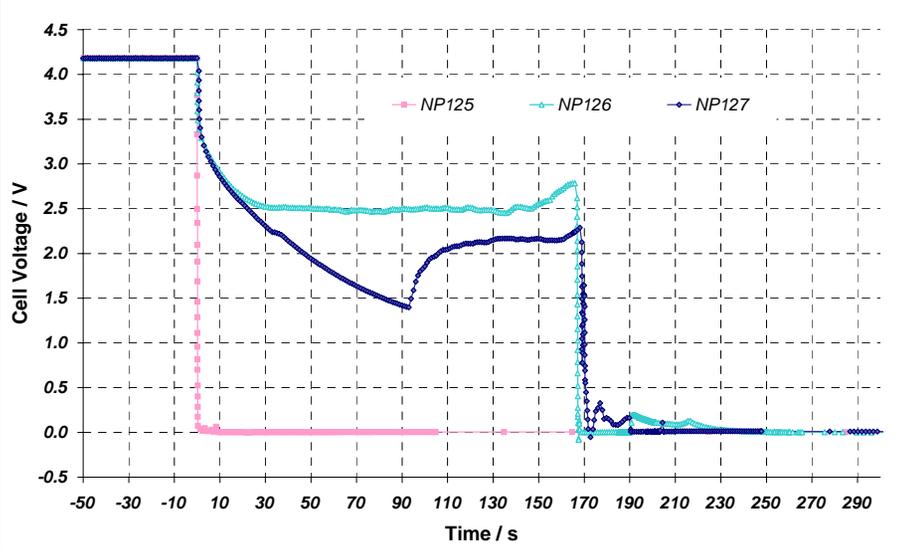


Cell Internal Short Circuit

- All 3 cells caught fire as cells cleave in 2
- Screw action test may leave soft short



No temperature data over 500°C





Cell DPA

- 2 cells disassembled, chemical composition analysed
- Electrolyte extracted with anhydrous methanol
 - Organic analysis
 - Inorganic analysis
 - Karl Fischer test (water content)
- SEM and EDAX examination
 - Anode
 - Cathode
- Separator analysis
 - IR spectroscopy
- Cell Construction inspection
 - Similar to all other 18650s encountered
- Cell burst and vent pressure measured
 - Burst ~47bar max Vent ~18bar max
 - Above 2.5 safety ratio

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Conclusions

- AEA selection and successful Interim Design Review for AHPS proves maturity of small cell approach for very large batteries
- Cells show excellent opportunity for battery mass reduction for AHPS and other low cycle applications
- Lack of cycle and extended calendar life make EOL battery performance difficult (AHPS 8 year mission)
- Preliminary design, AEA retained SONY 18650HC cell as baseline
 - Well characterised performance
 - Wealth of safety test data